

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of	:	Customer Number: 89518
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Hui-Mei Chen et al.	:	Confirmation Number: 3341
	:	
Application No.: 10/786,807	:	Group Art Unit: 2822
	:	
Filed: February 25, 2004	:	Examiner: Bac H. Au
	:	
For: METHOD FOR IMPROVING SEMICONDUCTOR WAFER TEST ACCURACY	:	

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I hereby certify that this correspondence is being electronically-transmitted to the
United States Patent and Trademark Office on **July 12, 2010.**
/Tobi A. Herbert/

Tobi A. Herbert

Sir:

This communication hereby notifies the United States Patent and Trademark Office of a change in status of the above-identified application from small entity to large entity. Any fees due in the above-identified application will be paid as large entity to reflect this change.

Respectfully submitted,
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